



PATENT

Docket No.: M4065.0215/P215

27E1
2787
#2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Eugene DeLaRosa et al.

Serial No.: 09/516,581 ✓

Filed: March 1, 2000 ✓

Group Art Unit: Not Yet Assigned

Examiner: Not Yet Assigned

RECEIVED
MAY 23 2000
TC 2700 MAIL ROOM

For: METHOD FOR MEASURING
REGISTRATION OF
OVERLAPPING MATERIAL
LAYERS OF AN INTEGRATED
CIRCUIT

Assistant Commissioner for Patents
Washington, D.C. 20231


SUBMISSION OF FORMAL DRAWINGS

Dear Sir:

Submitted herewith are five (5) sheets of five (5) figures of formal drawings for filing in the above-identified Patent Application. Kindly substitute the attached formal drawings for the informal drawings submitted with the originally filed application.

Dated: April 27, 2000

Respectfully submitted,

By 
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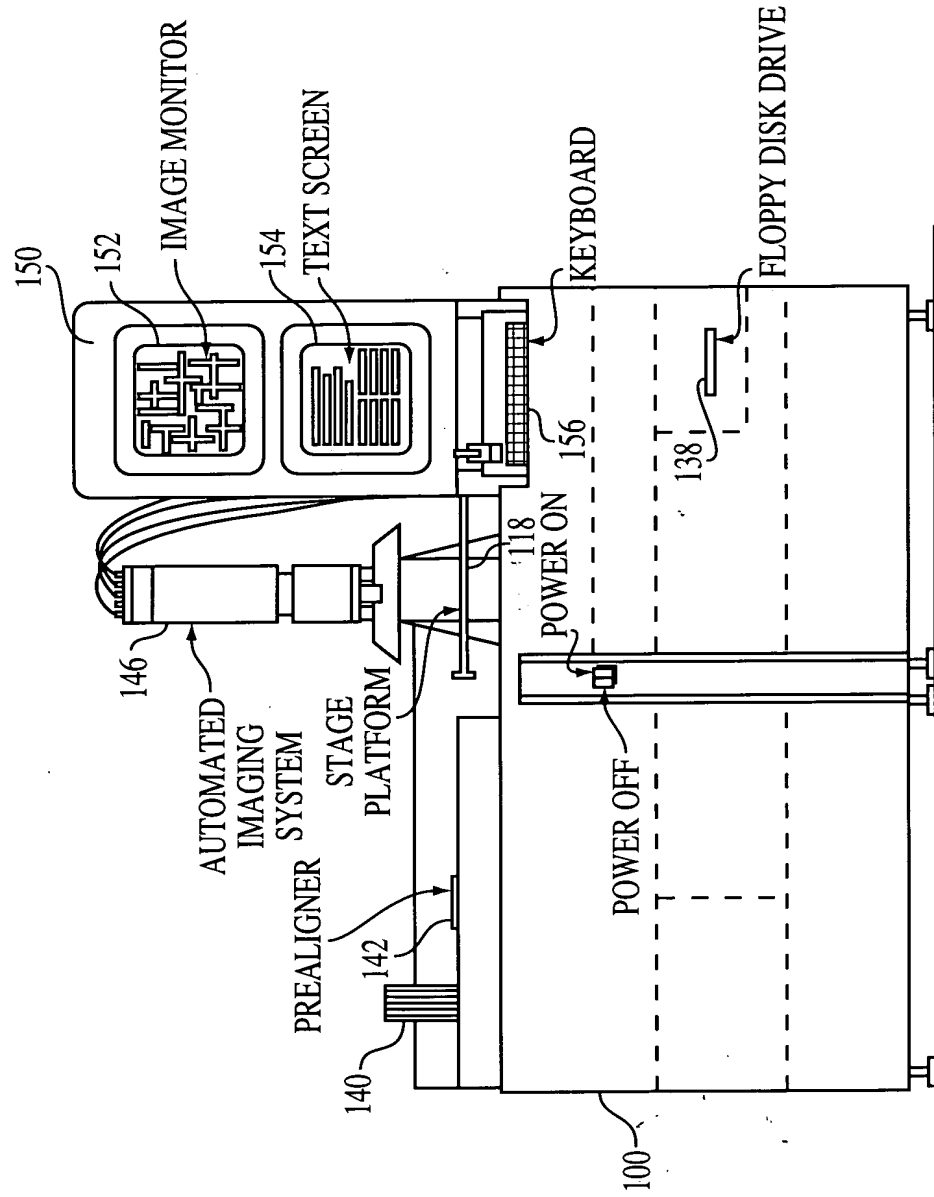


FIG. 1

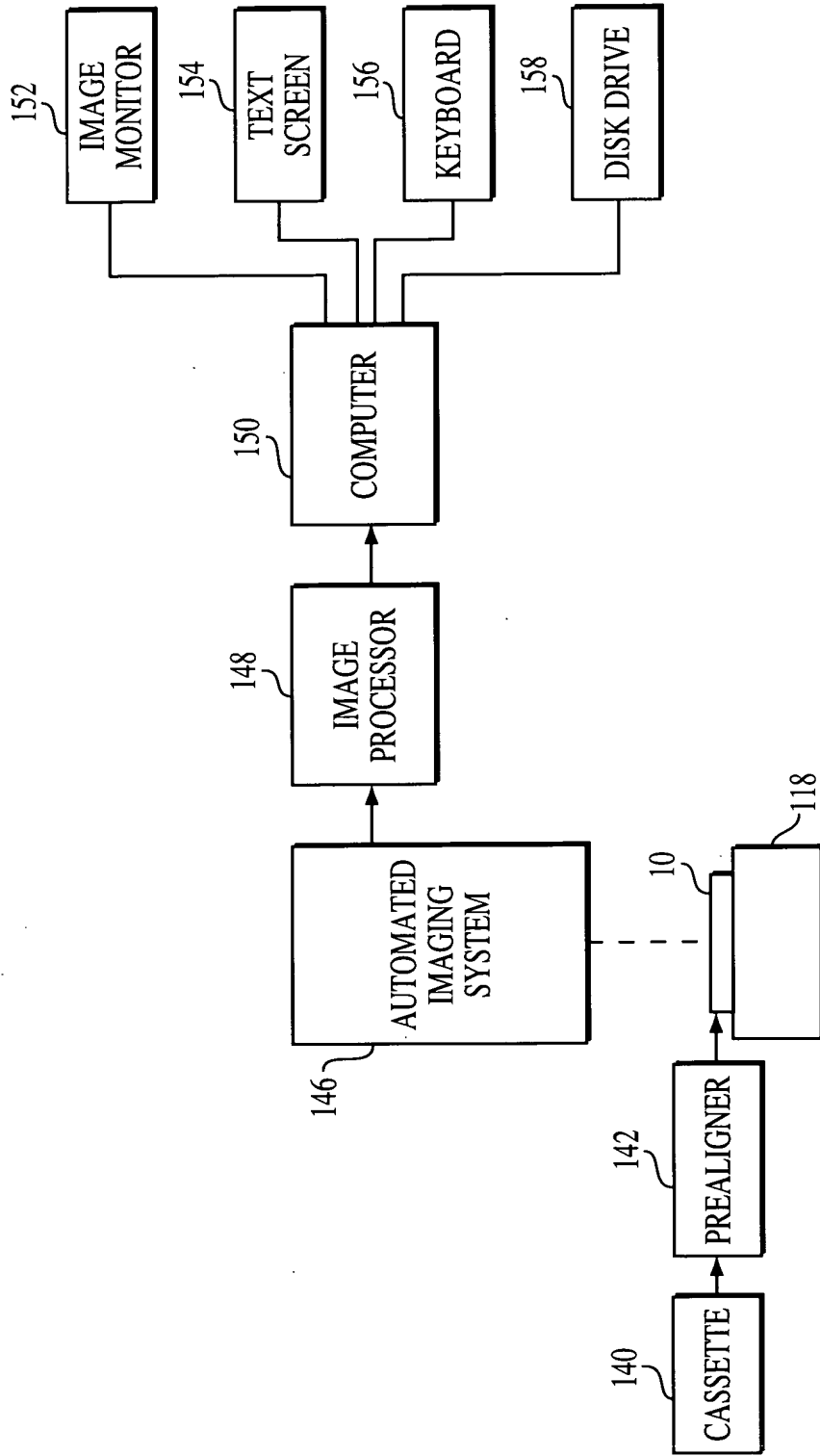


FIG. 2

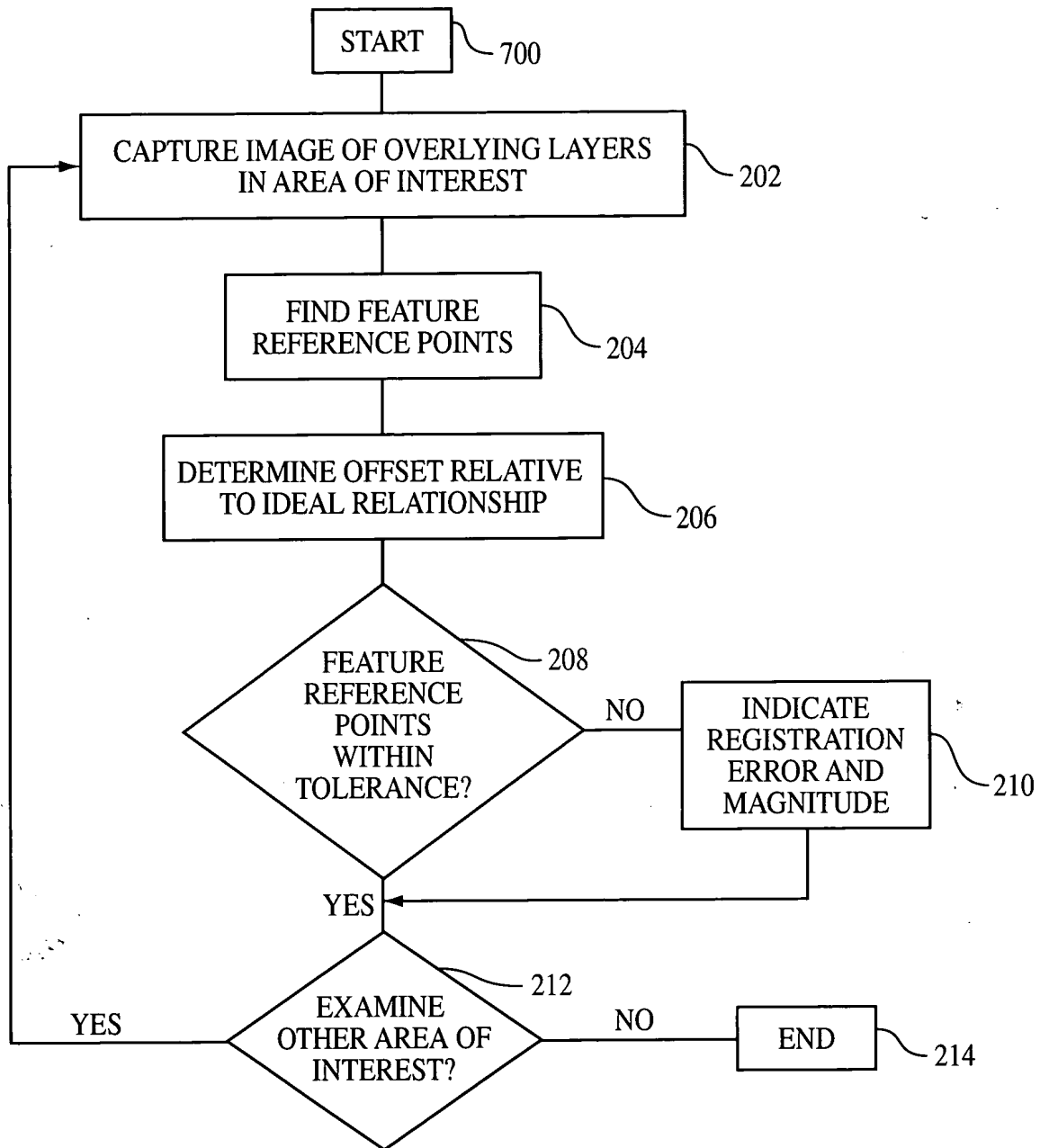


FIG. 3

APPROVED	O.G. FIG.	
BY	CLASS	SUBCLASS
DRAFTSMAN		

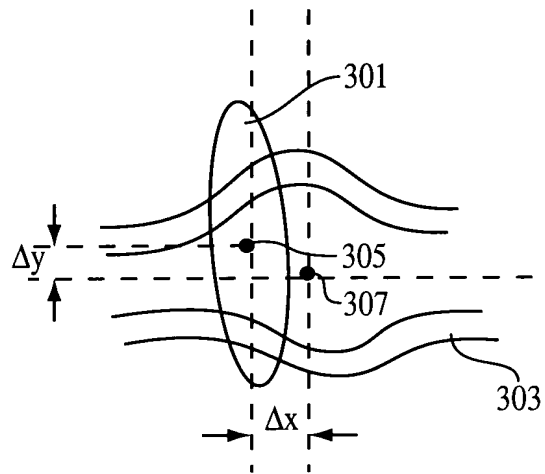


FIG. 4

APPROVED	O.G..FIG.	
BY	CLASS	SUBCLASS
DRAFTSMAN		

THE FOLLOWING IS AN AERIAL IMAGE 2D CONTOUR.

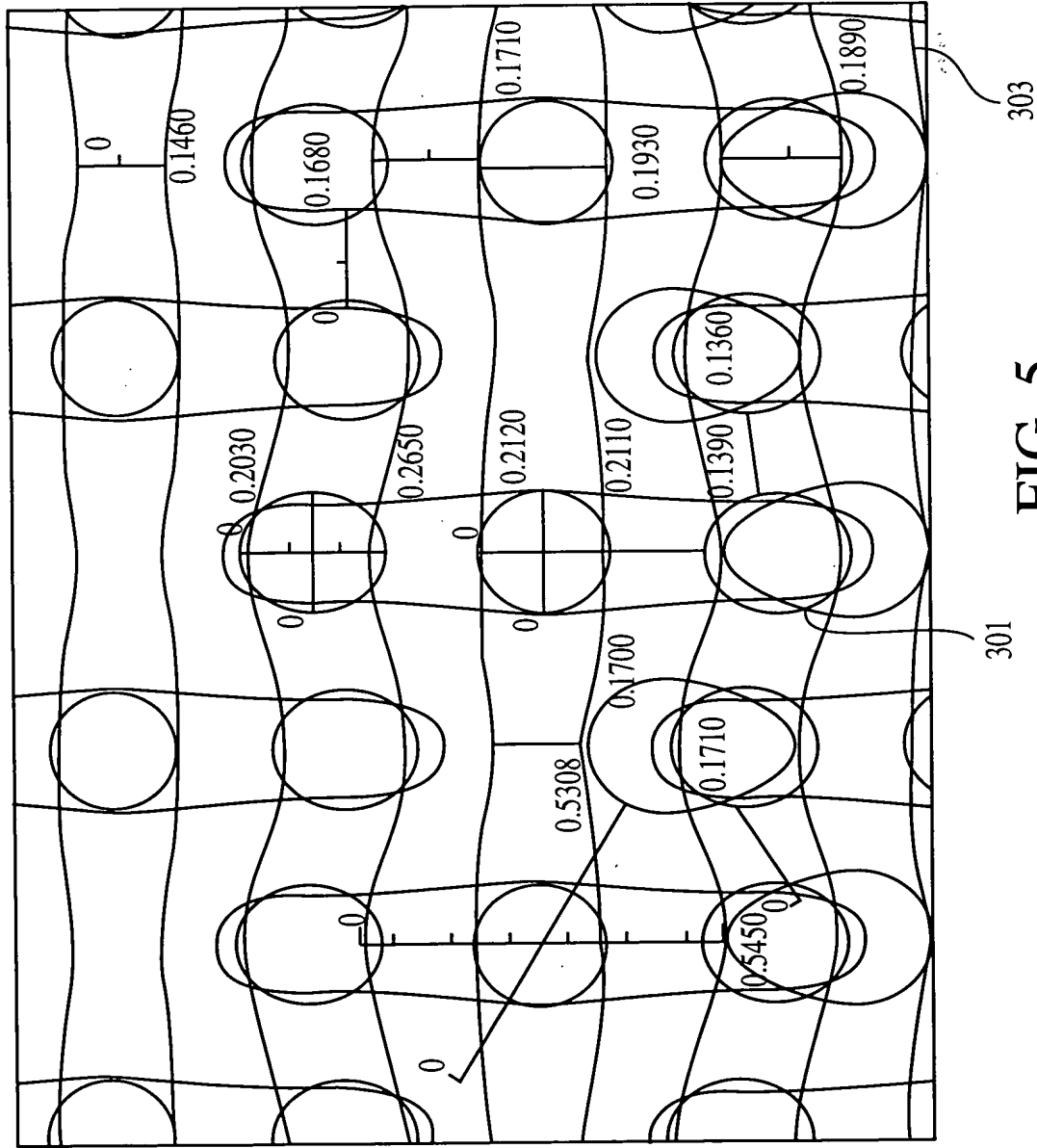


FIG. 5